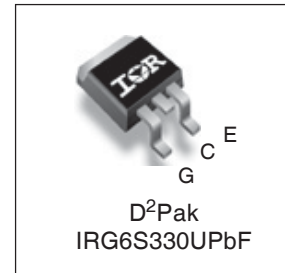
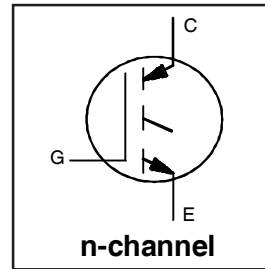


# IRG6S330UPbF

## Features

- Advanced Trench IGBT Technology
- Optimized for Sustain and Energy Recovery circuits in PDP applications
- Low  $V_{CE(on)}$  and Energy per Pulse ( $E_{PULSE}^{TM}$ ) for improved panel efficiency
- High repetitive peak current capability
- Lead Free package

Key Parameters		
$V_{CE\ min}$	330	V
$V_{CE(on)\ typ. @ I_C = 70A}$	1.80	V
$I_{RP\ max @ T_C = 25^\circ C}$	250	A
$T_J\ max$	150	$^\circ C$



G	C	E
Gate	Collector	Emitter

## Description

This IGBT is specifically designed for applications in Plasma Display Panels. This device utilizes advanced trench IGBT technology to achieve low  $V_{CE(on)}$  and low  $E_{PULSE}^{TM}$  rating per silicon area which improve panel efficiency. Additional features are 150 $^\circ C$  operating junction temperature and high repetitive peak current capability. These features combine to make this IGBT a highly efficient, robust and reliable device for PDP applications.

## Absolute Maximum Ratings

	Parameter	Max.	Units
$V_{GE}$	Gate-to-Emitter Voltage	$\pm 30$	V
$I_C @ T_C = 25^\circ C$	Continuous Collector Current, $V_{GE} @ 15V$	70	A
$I_C @ T_C = 100^\circ C$	Continuous Collector, $V_{GE} @ 15V$	40	
$I_{RP} @ T_C = 25^\circ C$	Repetitive Peak Current ①	250	
$P_D @ T_C = 25^\circ C$	Power Dissipation	160	W
$P_D @ T_C = 100^\circ C$	Power Dissipation	63	
	Linear Derating Factor	1.3	W/ $^\circ C$
$T_J$	Operating Junction and	-40 to + 150	$^\circ C$
$T_{STG}$	Storage Temperature Range		
	Soldering Temperature for 10 seconds	300	

## Thermal Resistance

	Parameter	Typ.	Max.	Units
$R_{\theta JC}$	Junction-to-Case ②	—	0.8	$^\circ C/W$

## Electrical Characteristics @ T<sub>J</sub> = 25°C (unless otherwise specified)

	Parameter	Min.	Typ.	Max.	Units	Conditions
BV <sub>CES</sub>	Collector-to-Emitter Breakdown Voltage	330	—	—	V	V <sub>GE</sub> = 0V, I <sub>CE</sub> = 1 mA
V <sub>(BR)ECS</sub>	Emitter-to-Collector Breakdown Voltage <sup>③</sup>	30	—	—	V	V <sub>GE</sub> = 0V, I <sub>CE</sub> = 1 A
ΔBV <sub>CES</sub> /ΔT <sub>J</sub>	Breakdown Voltage Temp. Coefficient	—	0.29	—	V/°C	Reference to 25°C, I <sub>CE</sub> = 1mA
V <sub>CE(on)</sub>	Static Collector-to-Emitter Voltage	—	1.25	—	V	V <sub>GE</sub> = 15V, I <sub>CE</sub> = 25A <sup>③</sup>
		—	1.43	—		V <sub>GE</sub> = 15V, I <sub>CE</sub> = 40A <sup>③</sup>
		—	1.80	2.10		V <sub>GE</sub> = 15V, I <sub>CE</sub> = 70A <sup>③</sup>
		—	2.38	—		V <sub>GE</sub> = 15V, I <sub>CE</sub> = 120A <sup>③</sup>
		—	2.10	—		V <sub>GE</sub> = 15V, I <sub>CE</sub> = 70A, T <sub>J</sub> = 150°C <sup>③</sup>
V <sub>GE(th)</sub>	Gate Threshold Voltage	2.6	—	5.0	V	V <sub>CE</sub> = V <sub>GE</sub> , I <sub>CE</sub> = 500μA
ΔV <sub>GE(th)</sub> /ΔT <sub>J</sub>	Gate Threshold Voltage Coefficient	—	-12	—	mV/°C	
I <sub>CES</sub>	Collector-to-Emitter Leakage Current	—	2.0	20	μA	V <sub>CE</sub> = 330V, V <sub>GE</sub> = 0V
		—	10	—		V <sub>CE</sub> = 330V, V <sub>GE</sub> = 0V, T <sub>J</sub> = 100°C
		—	40	200		V <sub>CE</sub> = 330V, V <sub>GE</sub> = 0V, T <sub>J</sub> = 125°C
		—	150	—		V <sub>CE</sub> = 330V, V <sub>GE</sub> = 0V, T <sub>J</sub> = 150°C
I <sub>GES</sub>	Gate-to-Emitter Forward Leakage	—	—	100	nA	V <sub>GE</sub> = 30V
	Gate-to-Emitter Reverse Leakage	—	—	-100	nA	V <sub>GE</sub> = -30V
g <sub>fe</sub>	Forward Transconductance	—	94	—	S	V <sub>CE</sub> = 25V, I <sub>CE</sub> = 25A
Q <sub>g</sub>	Total Gate Charge	—	86	—	nC	V <sub>CE</sub> = 200V, I <sub>C</sub> = 25A, V <sub>GE</sub> = 15V <sup>③</sup>
Q <sub>gc</sub>	Gate-to-Collector Charge	—	36	—		
t <sub>d(on)</sub>	Turn-On delay time	—	39	—		
t <sub>r</sub>	Rise time	—	32	—	ns	I <sub>C</sub> = 25A, V <sub>CC</sub> = 196V R <sub>G</sub> = 10Ω, L=200μH, L <sub>S</sub> = 150nH T <sub>J</sub> = 25°C
t <sub>d(off)</sub>	Turn-Off delay time	—	120	—		
t <sub>f</sub>	Fall time	—	55	—		
t <sub>d(on)</sub>	Turn-On delay time	—	37	—		
t <sub>r</sub>	Rise time	—	33	—	ns	I <sub>C</sub> = 25A, V <sub>CC</sub> = 196V R <sub>G</sub> = 10Ω, L=200μH, L <sub>S</sub> = 150nH T <sub>J</sub> = 150°C
t <sub>d(off)</sub>	Turn-Off delay time	—	159	—		
t <sub>f</sub>	Fall time	—	95	—		
t <sub>st</sub>	Shoot Through Blocking Time	100	—	—		
E <sub>PULSE</sub>	Energy per Pulse	—	943	—	μJ	L = 220nH, C= 0.40μF, V <sub>GE</sub> = 15V V <sub>CC</sub> = 240V, R <sub>G</sub> = 5.1Ω, T <sub>J</sub> = 25°C
		—	1086	—		L = 220nH, C= 0.40μF, V <sub>GE</sub> = 15V V <sub>CC</sub> = 240V, R <sub>G</sub> = 5.1Ω, T <sub>J</sub> = 100°C
ESD	Human Body Model	Class 2 (Per JEDEC standard JESD22-A114)				
	Machine Model	Class B (Per EIA/JEDEC standard EIA/JESD22-A115)				
C <sub>ies</sub>	Input Capacitance	—	2275	—	pF	V <sub>GE</sub> = 0V
C <sub>oes</sub>	Output Capacitance	—	108	—		V <sub>CE</sub> = 30V
C <sub>res</sub>	Reverse Transfer Capacitance	—	75	—		f = 1.0MHz, See Fig.13
L <sub>C</sub>	Internal Collector Inductance	—	4.5	—	nH	Between lead, 6mm (0.25in.)
L <sub>E</sub>	Internal Emitter Inductance	—	7.5	—		from package and center of die contact

### Notes:

- ① Half sine wave with duty cycle = 0.05, ton=2μsec.
- ② R<sub>θ</sub> is measured at T<sub>J</sub> of approximately 90°C.
- ③ Pulse width ≤ 400μs; duty cycle ≤ 2%.

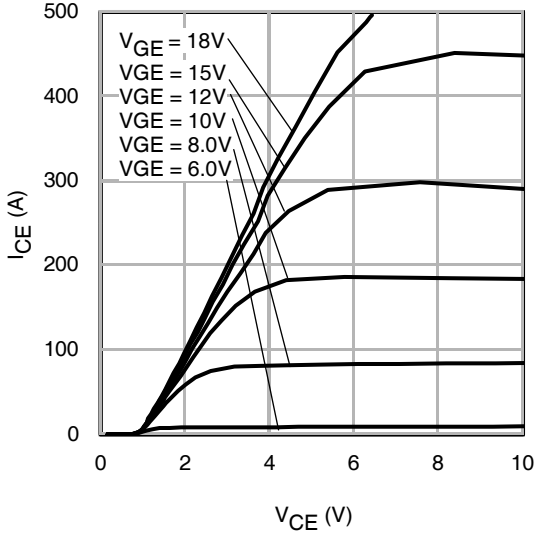


Fig 1. Typical Output Characteristics @ 25°C

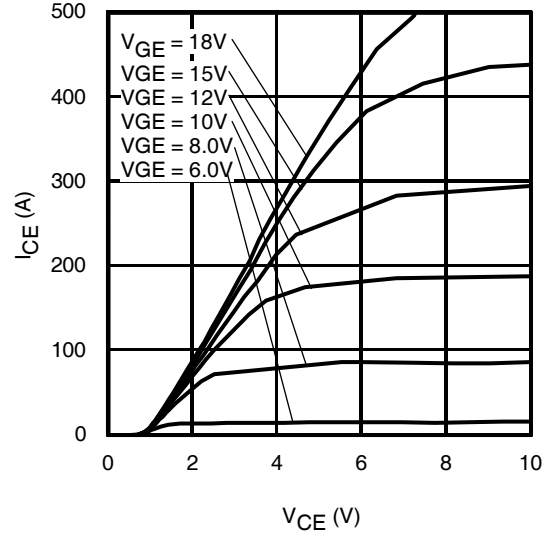


Fig 2. Typical Output Characteristics @ 75°C

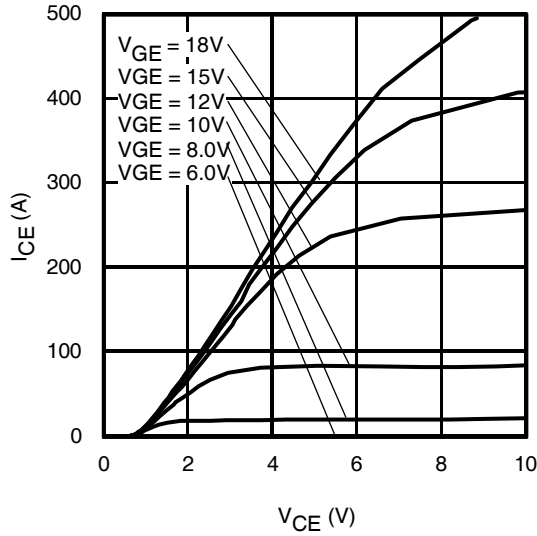


Fig 3. Typical Output Characteristics @ 125°C

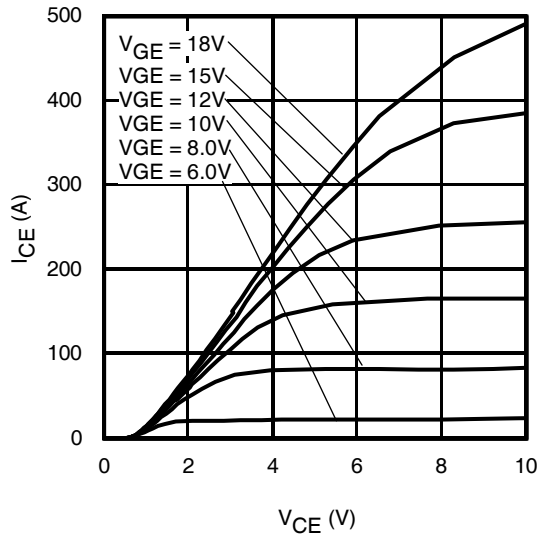


Fig 4. Typical Output Characteristics @ 150°C

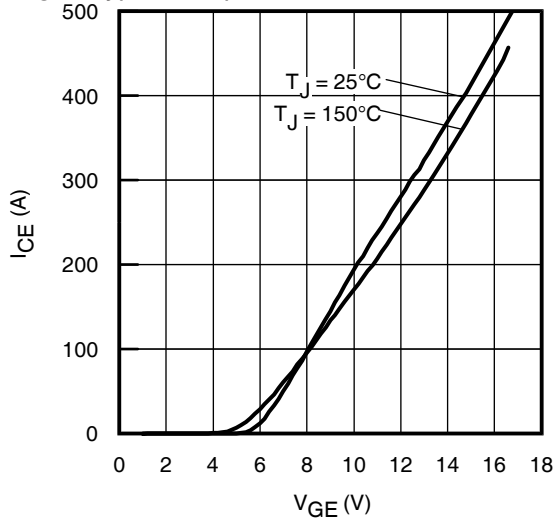


Fig 5. Typical Transfer Characteristics

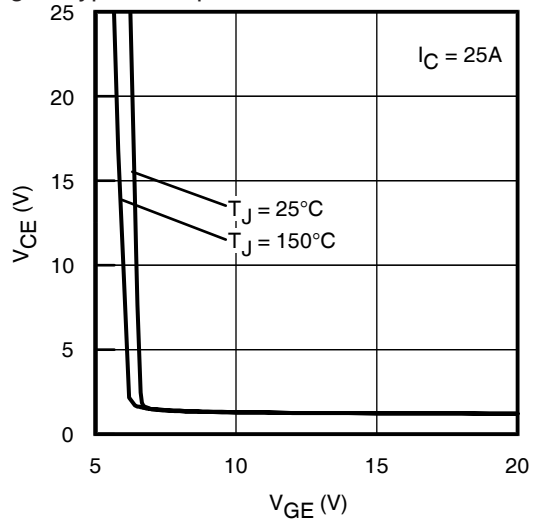


Fig 6.  $V_{CE(ON)}$  vs. Gate Voltage

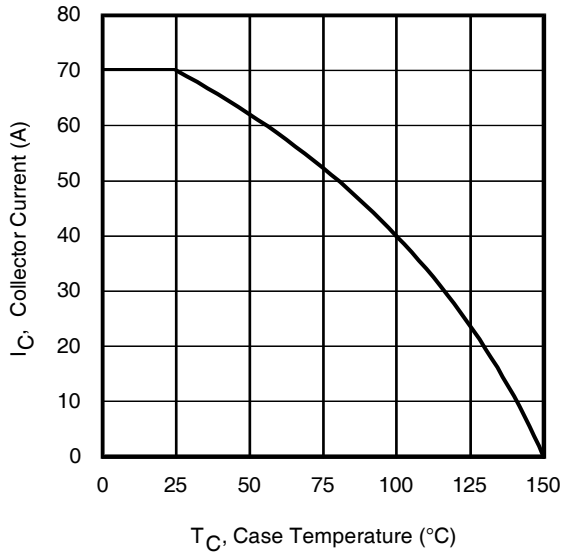


Fig 7. Maximum Collector Current vs. Case Temperature

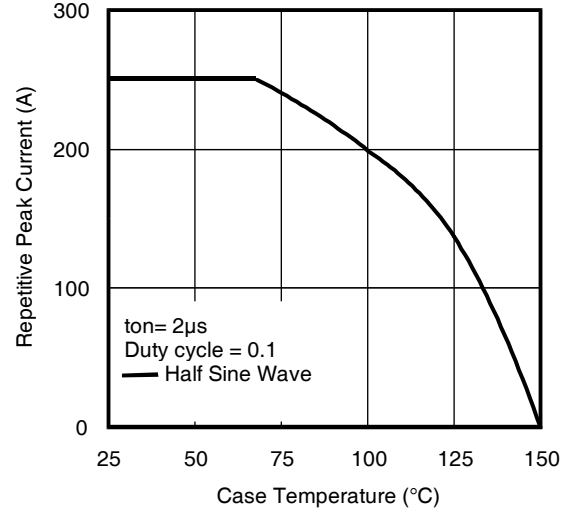


Fig 8. Typical Repetitive Peak Current vs. Case Temperature

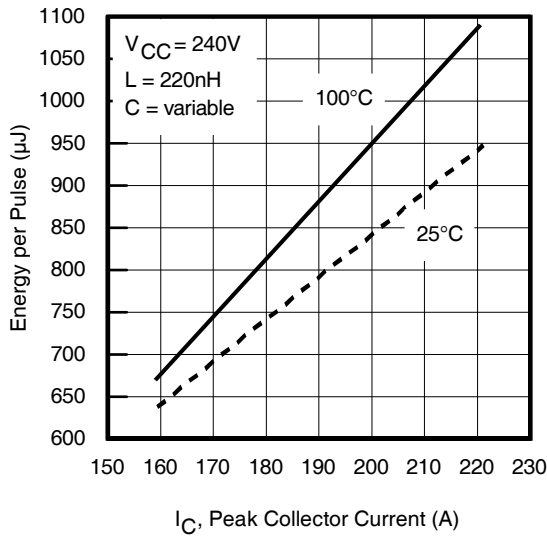


Fig 9. Typical  $E_{PULSE}$  vs. Collector Current

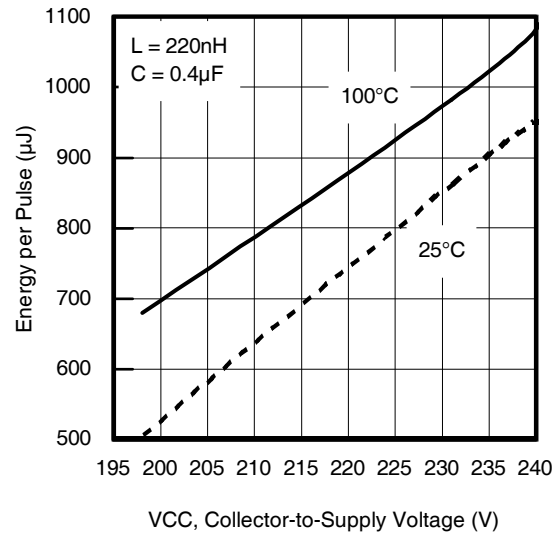


Fig 10. Typical  $E_{PULSE}$  vs. Collector-to-Supply Voltage

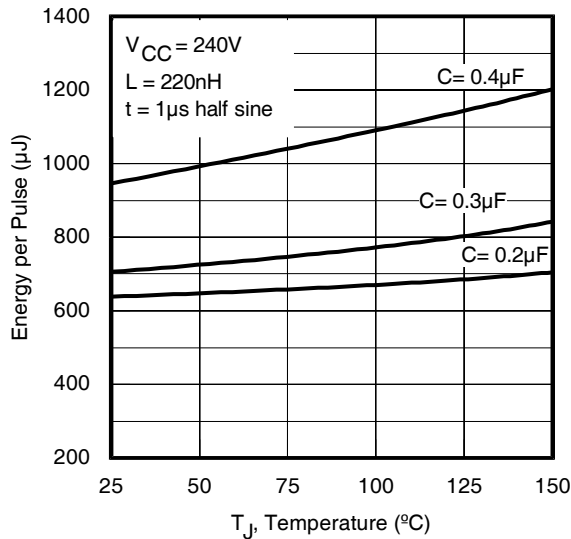


Fig 11.  $E_{PULSE}$  vs. Temperature

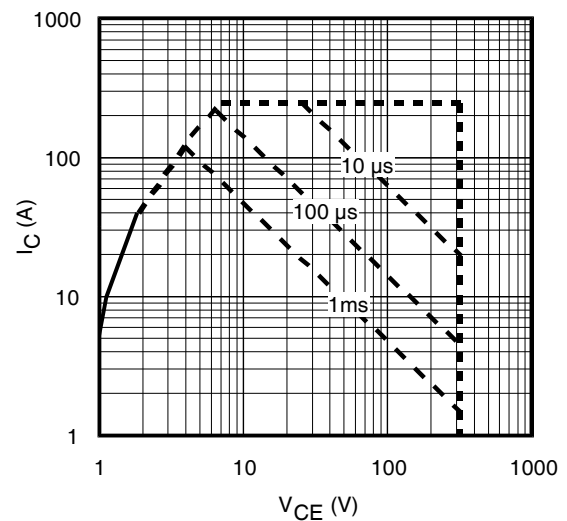


Fig 12. Forward Bias Safe Operating Area

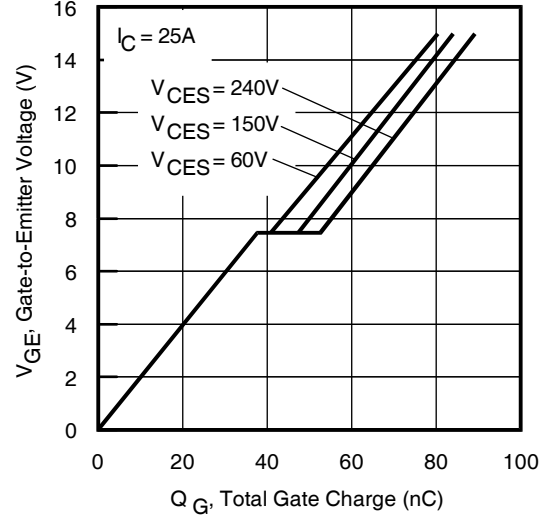
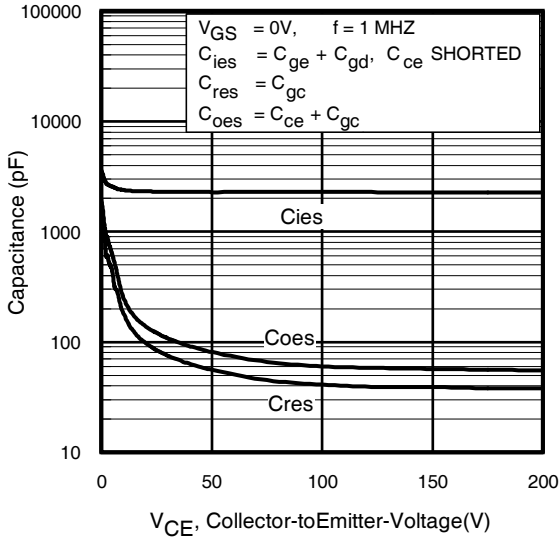


Fig 13. Typical Capacitance vs. Collector-to-Emitter Voltage

Fig 14. Typical Gate Charge vs. Gate-to-Emitter Voltage

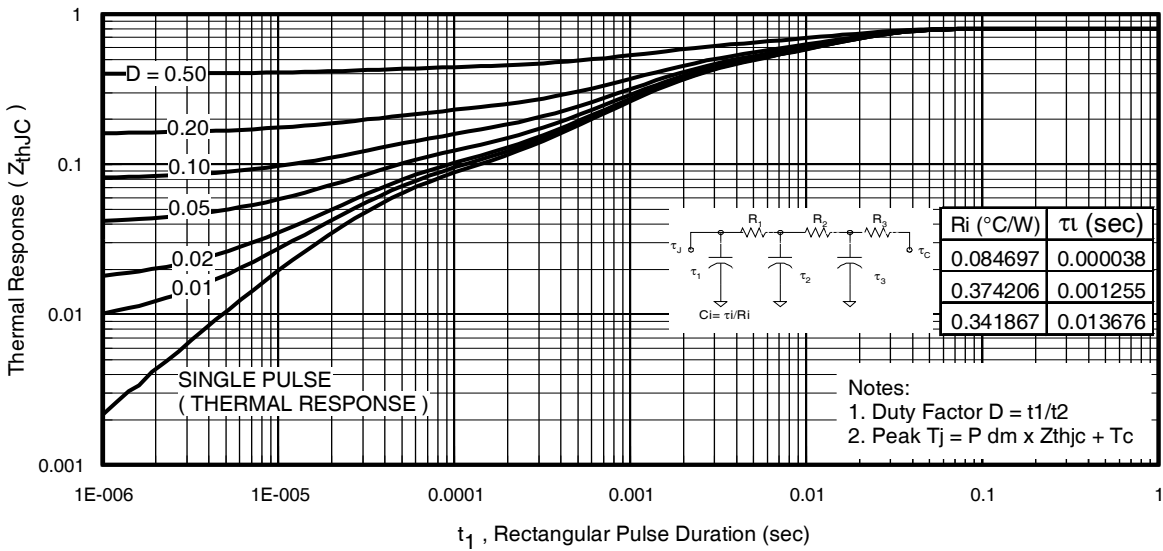
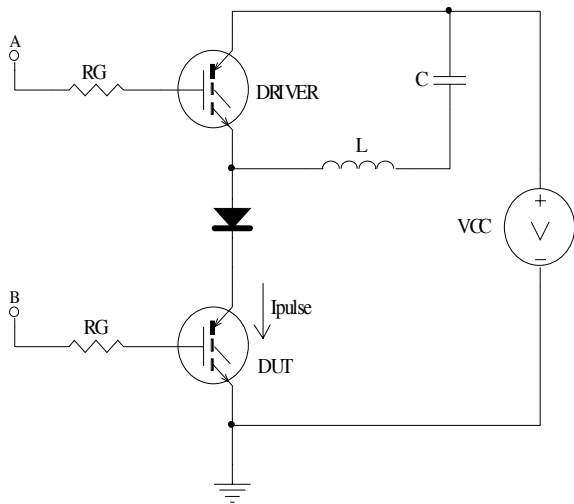
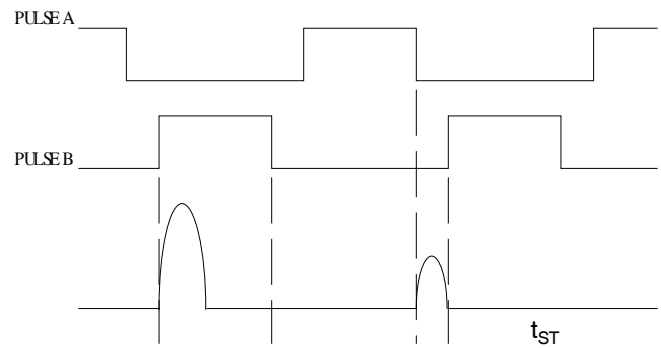


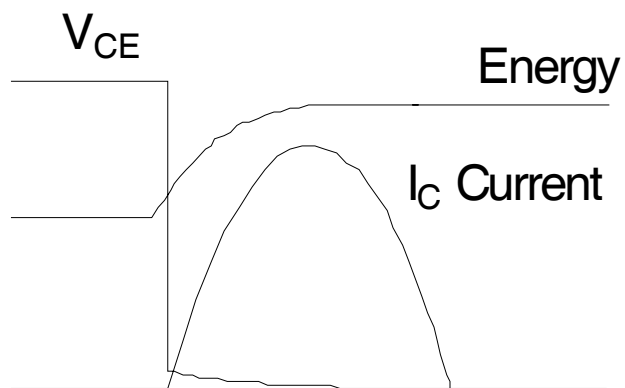
Fig 15. Maximum Effective Transient Thermal Impedance, Junction-to-Case



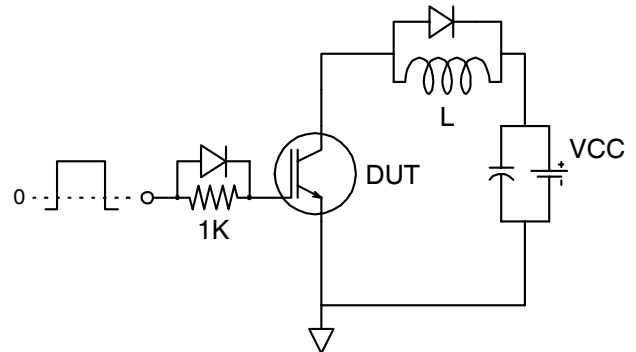
**Fig 16a.**  $t_{st}$  and  $E_{PULSE}$  Test Circuit



**Fig 16b.**  $t_{st}$  Test Waveforms



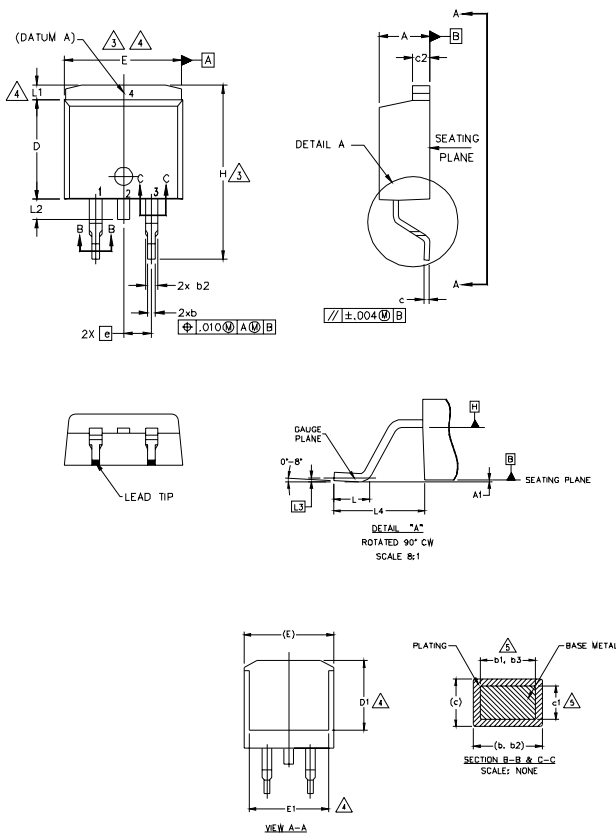
**Fig 16c.**  $E_{PULSE}$  Test Waveforms



**Fig. 17 -** Gate Charge Circuit (turn-off)

## D<sup>2</sup>Pak (TO-263AB) Package Outline

Dimensions are shown in millimeters (inches)



**NOTES:**

1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994
2. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES]
3. DIMENSION D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED 0.127 [0.005"] PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTMOST EXTREMES OF THE PLASTIC BODY AT DATUM H.
4. THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSION E, L1, D1 & E1.
5. DIMENSION b1 AND c1 APPLY TO BASE METAL ONLY.
6. DATUM A & B TO BE DETERMINED AT DATUM PLANE H.
7. CONTROLLING DIMENSION: INCH.
8. OUTLINE CONFORMS TO JEDEC OUTLINE TO-263AB.

SYMBOL	DIMENSIONS				NOTES
	MILLIMETERS		INCHES		
	MIN.	MAX.	MIN.	MAX.	
A	4.06	4.83	.160	.190	5
A1	0.00	0.254	.000	.010	
b	0.51	0.99	.020	.039	
b1	0.51	0.89	.020	.035	
b2	1.14	1.78	.045	.070	
b3	1.14	1.73	.045	.068	5
c	0.38	0.74	.015	.029	5
c1	0.38	0.58	.015	.023	
c2	1.14	1.65	.045	.065	
D	8.38	9.65	.330	.380	3
D1	6.86	-	.270	-	4
E	9.65	10.67	.380	.420	3,4
E1	6.22	-	.245	-	4
e	2.54 BSC		.100 BSC		4
H	14.61	15.88	.575	.625	
L	1.78	2.79	.070	.110	
L1	-	1.65	-	.066	
L2	1.27	1.78	-	.070	
L3	0.25 BSC		.010 BSC		
L4	4.78	5.28	.188	.208	

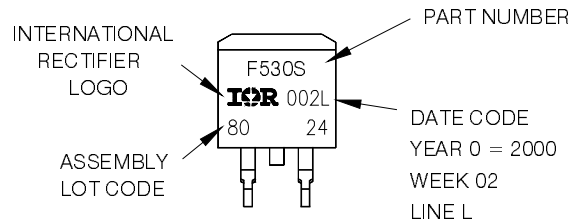
**LEAD ASSIGNMENTS**

- HEXFET**
- 1.- GATE
  - 2, 4.- DRAIN
  - 3.- SOURCE
- IGBTs, CoPACK**
- 1.- GATE
  - 2, 4.- COLLECTOR
  - 3.- EMITTER
- DIODES**
- 1.- ANODE \*
  - 2, 4.- CATHODE
  - 3.- ANODE
- \* PART DEPENDENT.

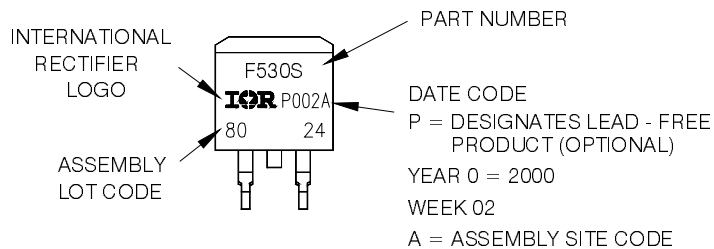
## D<sup>2</sup>Pak (TO-263AB) Part Marking Information

EXAMPLE: THIS IS AN IRF530S WITH  
LOT CODE 8024  
ASSEMBLED ON WW 02, 2000  
IN THE ASSEMBLY LINE "L"

Note: "P" in assembly line position  
indicates "Lead - Free"



OR

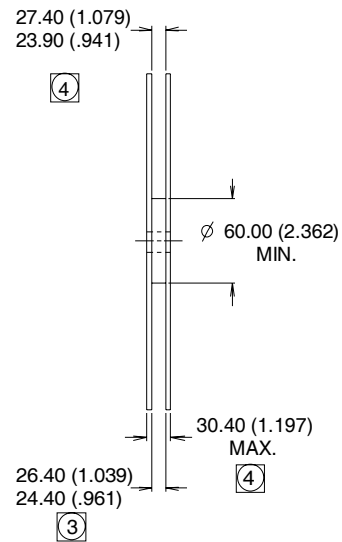
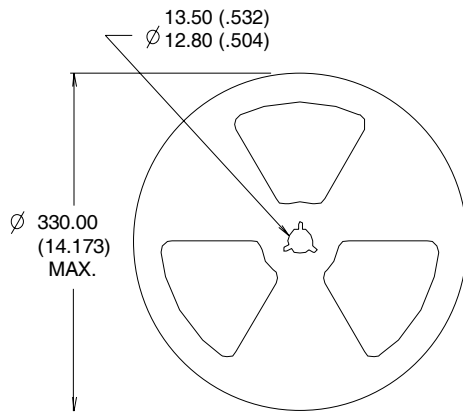
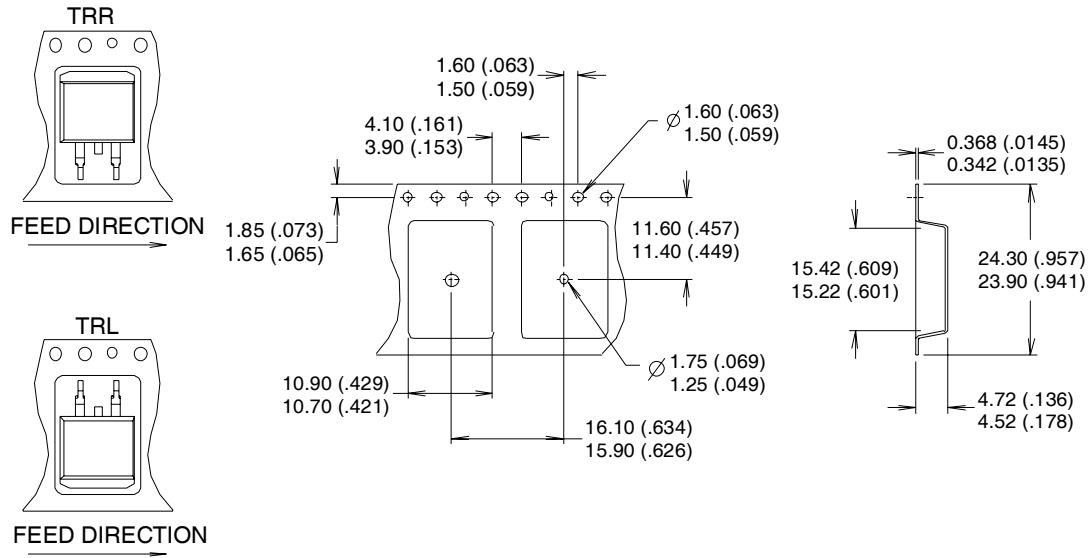


Note: For the most current drawing please refer to IR website at <http://www.irf.com/package/>

# IRG6S330UPbF

## D<sup>2</sup>Pak (TO-263AB) Tape & Reel Information

Dimensions are shown in millimeters (inches)



- NOTES :
1. COMFORMS TO EIA-418.
  2. CONTROLLING DIMENSION: MILLIMETER.
  - ③ DIMENSION MEASURED @ HUB.
  - ④ INCLUDES FLANGE DISTORTION @ OUTER EDGE.

**Note:** For the most current drawing please refer to IR website at <http://www.irf.com/package/>

Data and specifications subject to change without notice.  
This product has been designed for the Industrial market.  
Qualification Standards can be found on IR's Web site.